Search Notes



Ap	plication/Control No.	Applicant(s)/Patent Under Reexamination
105	583181	D'AMATO, GIANFRANCO
Exa	aminer	Art Unit
СН	RISTOPHER DEMEREE	3782

SEARCHED					
Class	Subclass	Date	Examiner		
229	4.5, 932	1/12/2009	CD		
206	562	12/29/2009	CD		
220	665 680 678 676 670 659 657 656	12/30/2009	CD		

SEARCH NOTES				
Search Notes	Date	Examiner		
Conducted a PLUS search on the application	1/12/2009	CD		
Conducted a text search for (tamper or inspection) and B65D 3/6	1/12/2009	CD		
Updated search	7/7/2009	CD		
Consulted examiner, Robert Hicks, for search assistance in class 220. Subclasses 665, 662, 680, 678, 676, 670, 669, 62, 659, 657 and 656 were suggested.	12/30/2009	CD		
Conducted a text search for ((peripheral or edge) near5 (hole or opening or aperture)) with overlap\$4) AND (229.clas. or 220.clas. or 206.clas.)	12/29/2009	CD		
Conducted a text search for ((recess\$3 or open\$3) with (edge or peripher\$2)) AND (220/662 or 220/669 or 220/62)	12/30/2009	CD		
Updated search	7/20/2010	CD		
Updated search	2/2/2011	CD		

INTERFERENCE SEARCH				
Subclass	Date	Examiner		

/CHRISTOPHER DEMEREE/ Examiner.Art Unit 3782	

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